



Express Mail No. ER 843 147 155 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: McElheny, et al.

Confirmation No.: 8609

Serial No.: 10/800,221

Art Unit: 2812

Filed: March 11, 2004

Examiner: Walter Lee Lindsay, Jr.

For: DUAL-OXIDE TRANSISTORS
FOR THE IMPROVEMENT OF
RELIABILITY AND OFF-
STATE LEAKAGE

Attorney Docket No: 060889-5002

FEE TRANSMITTAL SHEET

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The fee required to be filed with the accompanying amendment of even date herewith concerning the above-identified application has been estimated to be \$0.00.

The claim amendment fee has been estimated as shown below:

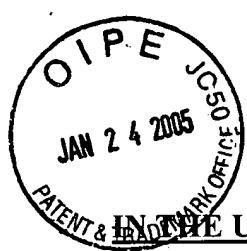
(Col. 1)	(Col. 2)	(Col. 3)	<input type="checkbox"/> SMALL ENTITY			<input type="checkbox"/> OTHER THAN A SMALL ENTITY		
CLAIMS REMAINING AFTER AMENDMENT	HIGHEST NO. PREVIOUSLY PAID	PRESENT EXTRA	RATE	ADDIT. FEE	OR	RATE	ADDIT. FEE	
TOTAL 11	MINUS 20		x 25	\$		x 50	\$	0
INDEP. 3	MINUS 3		x 100	\$		x 200	\$	0
				\$			\$	0.00
<input type="checkbox"/> FIRST PRESENTATION OF MULTIPLE DEP. CLAIM			TOTAL	\$	OR	TOTAL	\$	0.00

Please charge the required fee to Morgan, Lewis & Bockius LLP Deposit Account No. 50-0310. A copy of this sheet is enclosed.

Respectfully submitted,

Date: January 24, 2005

Francis E Morris 24,615
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AMENDMENT

MAIL STOP AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

The enclosed Amendment is in response to the Office Action dated September 23, 2004 for the above identified patent application.